

Satoshi Ninomiya

List of Publications by Year in descending order

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96
papers

1,585
citations

361045

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h-index

344852

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all docs

96
docs citations

96
times ranked

904
citing authors

#	ARTICLE	IF	CITATIONS
1	Comparative study of H ₃ O ⁺ (aq) and NH ₄ ⁺ (aq) on electrophoresis, protonating ability, and sodiation of proteins. <i>International Journal of Mass Spectrometry</i> , 2022, 471, 116728.	0.7	5
2	Negative-mode mass spectrometric study on dc corona, ac corona and dielectric barrier discharge ionization in ambient air containing H ₂ O ₂ , 2,4,6-trinitrotoluene (TNT), and 1,3,5-trinitroperhydro-1,3,5-triazine (RDX). <i>International Journal of Mass Spectrometry</i> , 2021, 459, 116440.	0.7	10
3	Miniaturized String Sampling Probe and Electrospray Extraction/Ionization within the Ion Inlet Tube for Mass Spectrometric Endoscopy. <i>Journal of the American Society for Mass Spectrometry</i> , 2021, 32, 606-610.	1.2	5
4	Electrospray based Mass Spectrometry. <i>Hyomen Gijutsu/Journal of the Surface Finishing Society of Japan</i> , 2021, 72, 162-168.	0.1	0
5	Reaction of CO ₃ ^{•-} with trinitrotoluene (TNT) in CO ₂ plasma: Experimental and theoretical study on the formation of [TNT ⁺ O] ^{•+} and its fragmentation pathways. <i>International Journal of Mass Spectrometry</i> , 2021, 467, 116622.	0.7	2
6	Corona Discharge and Field Electron Emission in Ambient Air Using a Sharp Metal Needle: Formation and Reactivity of CO ₃ ^{•-} and O ₂ ^{•-} . <i>Mass Spectrometry</i> , 2021, 10, A0100-A0100.	0.2	2
7	Rapid desorption of low-volatility compounds in liquid droplets accompanied by the flash evaporation of solvent below the Leidenfrost temperature. <i>Rapid Communications in Mass Spectrometry</i> , 2020, 34, e8535.	0.7	2
8	Point Analysis of Foods by Sheath-Flow Probe Electrospray Ionization/Mass Spectrometry (sfPESI/MS) Coupled with a Touch Sensor. <i>Journal of Agricultural and Food Chemistry</i> , 2020, 68, 418-425.	2.4	9
9	Flash desorption of low-volatility compounds deposited on a heated solid substrate (90°C) by dripping liquid methanol. <i>Rapid Communications in Mass Spectrometry</i> , 2020, 34, e8949.	0.7	3
10	Robotic sheath-flow probe electrospray ionization/mass spectrometry (sfPESI/MS): development of a touch sensor for samples in a multiwell plastic plate. <i>Analytical Methods</i> , 2020, 12, 2812-2819.	1.3	4
11	Pulsed Nano-Electrospray Ionization with a High Voltage (4000 V) Pulse Applied to Solutions in the Range of 200 ns to 1 ms. <i>Journal of the American Society for Mass Spectrometry</i> , 2020, 31, 693-699.	1.2	9
12	A novel contrast of the reactions of 2,4,6-trinitrotoluene (TNT) in atmospheric-pressure O ₂ and N ₂ plasma: Experimental and theoretical study. <i>International Journal of Mass Spectrometry</i> , 2020, 450, 116308.	0.7	5
13	Probe Electrospray Ionization (PESI) and Its Modified Versions: Dipping PESI (dPESI), Sheath-Flow PESI (sfPESI) and Adjustable sfPESI (ad-sfPESI). <i>Mass Spectrometry</i> , 2020, 9, A0092-A0092.	0.2	17
14	Sheath-flow probe electrospray ionization (sfPESI) mass spectrometry for the rapid forensic analysis of human body fluids. <i>Analytical Methods</i> , 2019, 11, 3633-3640.	1.3	9
15	Real-time analysis of living animals and rapid screening of human fluid samples using remote sampling electrospray ionization mass spectrometry. <i>Journal of Pharmaceutical and Biomedical Analysis</i> , 2019, 172, 372-378.	1.4	6
16	Component Profiling in Agricultural Applications Using an Adjustable Acupuncture Needle for Sheath-Flow Probe Electrospray Ionization/Mass Spectrometry. <i>Journal of Agricultural and Food Chemistry</i> , 2019, 67, 3275-3283.	2.4	12
17	Probe electrospray ionization of mixture solutions using metal needles with different tip conditions. <i>Surface and Interface Analysis</i> , 2019, 51, 100-104.	0.8	2
18	Dipping probe electrospray ionization/mass spectrometry for direct on-site and low-invasive food analysis. <i>Food Chemistry</i> , 2018, 260, 53-60.	4.2	16

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19	Electrospray ionization source with a rear extractor. <i>Journal of Mass Spectrometry</i> , 2018, 53, 400-407.	0.7	7
20	Remote sampling mass spectrometry for dry samples: Sheath-flow probe electrospray ionization (PESI) using a gel-loading tip inserted with an acupuncture needle. <i>Rapid Communications in Mass Spectrometry</i> , 2018, 32, 407-413.	0.7	14
21	Hyphenation of high-temperature liquid chromatography with high-pressure electrospray ionization for subcritical water LC-ESI-MS. <i>Analyst, The</i> , 2018, 143, 5552-5558.	1.7	14
22	Evaluation of Mass and Charge state of the Droplets Produced by Vacuum Electrospray of Aqueous Solutions. <i>Vacuum and Surface Science</i> , 2018, 61, 286-291.	0.0	0
23	Development of a Vacuum Electrospray Droplet Ion Gun for Secondary Ion Mass Spectrometry. <i>Mass Spectrometry</i> , 2018, 7, A0069-A0069.	0.2	12
24	Electrospray Generated from the Tip-Sealed Fine Glass Capillary Inserted with an Acupuncture Needle Electrode. <i>Journal of the American Society for Mass Spectrometry</i> , 2018, 29, 2297-2304.	1.2	5
25	Relative secondary ion yields produced by vacuum-type electrospray droplet ion beams. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2018, 36, 03F134.	0.6	10
26	Development of a Vacuum-type Electrospray Droplet Ion Gun and Its Application to Time-of-flight Secondary Ion Mass Spectrometry. <i>Vacuum and Surface Science</i> , 2018, 61, 440-445.	0.0	0
27	In vivo endoscopic mass spectrometry using a moving string sampling probe. <i>Analyst, The</i> , 2017, 142, 2735-2740.	1.7	12
28	Analysis of fluorene and 9,9-dialkylfluorenes by electrospray droplet impact (EDI)/SIMS. <i>International Journal of Mass Spectrometry</i> , 2017, 419, 29-36.	0.7	0
29	Pulsed probe electrospray and nano-electrospray: the temporal profiles of ion formation from the Taylor cone. <i>Analytical Methods</i> , 2017, 9, 4958-4963.	1.3	7
30	Sputtering properties for polyimide by vacuum electrospray droplet impact (V-EDI) using size-selected cluster ions. <i>Surface and Interface Analysis</i> , 2017, 49, 127-132.	0.8	2
31	Development of an Ion Gun Using Vacuum Electrospray. <i>Journal of the Vacuum Society of Japan</i> , 2017, 60, 321-327.	0.3	3
32	Development of Remote Sampling ESI Mass Spectrometry for the Rapid and Automatic Analysis of Multiple Samples. <i>Mass Spectrometry</i> , 2017, 5, S0068-S0068.	0.2	5
33	Desorption in Mass Spectrometry. <i>Mass Spectrometry</i> , 2017, 6, S0059-S0059.	0.2	9
34	Secondary Ion Mass Spectrometry Analysis of Renal Cell Carcinoma with Electrospray Droplet Ion Beams. <i>Mass Spectrometry</i> , 2017, 6, A0053-A0053.	0.2	2
35	Towards Practical Endoscopic Mass Spectrometry. <i>Mass Spectrometry</i> , 2017, 6, S0070-S0070.	0.2	2
36	Super-atmospheric pressure ionization mass spectrometry and its application to ultrafast online protein digestion analysis. <i>Journal of Mass Spectrometry</i> , 2016, 51, 396-411.	0.7	17

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37	Secondary ions produced by electrospray droplet impact with m/z selection from 103 to 106. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2016, 34, 03H116.	0.6	6
38	Secondary ion yields for vacuum-type electrospray droplet beams measured with a triple focus time-of-flight analyzer. <i>Rapid Communications in Mass Spectrometry</i> , 2016, 30, 2279-2284.	0.7	15
39	Probe Electrospray Ionization Mass Spectrometry with Discontinuous Atmospheric Pressure Interface. <i>European Journal of Mass Spectrometry</i> , 2015, 21, 327-334.	0.5	20
40	Rapid Online Non-Enzymatic Protein Digestion Analysis with High Pressure Superheated ESI-MS. <i>Journal of the American Society for Mass Spectrometry</i> , 2015, 26, 1085-1091.	1.2	13
41	XPS depth analysis of metal/polymer multilayer by vacuum electrospray droplet impact. <i>Surface and Interface Analysis</i> , 2015, 47, 77-81.	0.8	15
42	Piezoelectric inkjet assisted rapid electrospray ionization mass spectrometric analysis of metabolites in plant single cells via a direct sampling probe. <i>Analyst, The</i> , 2014, 139, 5734-5739.	1.7	30
43	Desorption Mass Spectrometry for Nonvolatile Compounds Using an Ultrasonic Cutter. <i>Journal of the American Society for Mass Spectrometry</i> , 2014, 25, 1177-1180.	1.2	17
44	Evaluation of a diode laser-assisted vacuum-type charged droplet beam source. <i>Surface and Interface Analysis</i> , 2014, 46, 364-367.	0.8	7
45	Characteristics of Charged Droplet Beams Produced from Vacuum Electrospray. <i>Journal of Surface Analysis (Online)</i> , 2014, 20, 171-176.	0.1	8
46	Development of a high-performance electrospray droplet beam source. <i>Surface and Interface Analysis</i> , 2013, 45, 126-130.	0.8	10
47	Threshold behaviour of ion formation for noble metals (Au, Ag, Cu, Pt) irradiated by 4ns 532nm laser. <i>International Journal of Mass Spectrometry</i> , 2013, 341-342, 45-51.	0.7	4
48	Development of sheath-flow probe electrospray ionization (SF-PEESI). <i>Journal of Mass Spectrometry</i> , 2013, 48, 823-829.	0.7	23
49	Flash Desorption/Mass Spectrometry for the Analysis of Less- and Nonvolatile Samples Using a Linearly Driven Heated Metal Filament. <i>Journal of the American Society for Mass Spectrometry</i> , 2013, 24, 1727-1735.	1.2	29
50	Alternating current corona discharge/atmospheric pressure chemical ionization for mass spectrometry. <i>Rapid Communications in Mass Spectrometry</i> , 2013, 27, 2760-2766.	0.7	18
51	Trace Level Detection of Explosives in Solution Using Leidenfrost Phenomenon Assisted Thermal Desorption Ambient Mass Spectrometry. <i>Mass Spectrometry</i> , 2013, 2, S0008-S0008.	0.2	30
52	Solid probe assisted nanoelectrospray ionization mass spectrometry for biological tissue diagnostics. <i>Analyst, The</i> , 2012, 137, 4658.	1.7	29
53	XPS depth analysis of CuO by electrospray droplet impact. <i>Surface and Interface Analysis</i> , 2012, 44, 938-941.	0.8	45
54	Vacuum electrospray of volatile liquids assisted by infrared laser irradiation. <i>Rapid Communications in Mass Spectrometry</i> , 2012, 26, 863-869.	0.7	35

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55	Development of double cylindrical dielectric barrier discharge ion source. <i>Analyst, The</i> , 2011, 136, 1210.	1.7	23
56	Highly sensitive molecular detection with swift heavy ions. <i>Nuclear Instruments & Methods in Physics Research B</i> , 2011, 269, 2251-2253.	0.6	19
57	Using ellipsometry for the evaluation of surface damage and sputtering yield in organic films with irradiation of argon cluster ion beams. <i>Surface and Interface Analysis</i> , 2011, 43, 84-87.	0.8	9
58	Analysis of organic semiconductor multilayers with Ar cluster secondary ion mass spectrometry. <i>Surface and Interface Analysis</i> , 2011, 43, 95-98.	0.8	36
59	The effect of incident energy on molecular depth profiling of polymers with large Ar cluster ion beams. <i>Surface and Interface Analysis</i> , 2011, 43, 221-224.	0.8	23
60	X-ray photoelectron spectroscopy depth analysis of metal oxides by electrospray droplet impact. <i>Surface and Interface Analysis</i> , 2011, 43, 1605-1609.	0.8	36
61	Evaluation of Surface Damage of Organic Films due to Irradiation with Energetic Ion Beams. <i>AIP Conference Proceedings</i> , 2011, , .	0.3	1
62	Low-damage milling of an amino acid thin film with cluster ion beam. <i>Journal of Applied Physics</i> , 2011, 110, 094701.	1.1	2
63	Biomolecular Emission by Swift Heavy Ion Bombardment. , 2011, , .		1
64	Anisotropic Etching Using Reactive Cluster Beams. <i>Applied Physics Express</i> , 2010, 3, 126501.	1.1	12
65	MeV-energy probe SIMS imaging of major components in animal cells etched using large gas cluster ions. <i>Nuclear Instruments & Methods in Physics Research B</i> , 2010, 268, 1736-1740.	0.6	17
66	SIMS with highly excited primary beams for molecular depth profiling and imaging of organic and biological materials. <i>Surface and Interface Analysis</i> , 2010, 42, 1612-1615.	0.8	34
67	Processing Techniques of Biomaterials Using Ar Cluster Ion Beam for Imaging Mass Spectrometry. <i>Transactions of the Materials Research Society of Japan</i> , 2010, 35, 793-796.	0.2	0
68	Development of a Remote-from-Plasma Dielectric Barrier Discharge Ion Source and Its Application to Explosives. <i>Journal of the Mass Spectrometry Society of Japan</i> , 2010, 58, 215-220.	0.0	15
69	Evaluation of Damage Layer in an Organic Film with Irradiation of Energetic Ion Beams. <i>Japanese Journal of Applied Physics</i> , 2010, 49, 036503.	0.8	12
70	SIMS Depth Profiling of Organic Materials with Ar Cluster Ion Beam. <i>Transactions of the Materials Research Society of Japan</i> , 2010, 35, 785-788.	0.2	0
71	Sputtering yield measurements with size-selected gas cluster ion beams. <i>Materials Research Society Symposia Proceedings</i> , 2009, 1181, 150.	0.1	4
72	Matrix-free high-resolution imaging mass spectrometry with high-energy ion projectiles. <i>Journal of Mass Spectrometry</i> , 2009, 44, 128-136.	0.7	46

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73	The emission process of secondary ions from solids bombarded with large gas cluster ions. Nuclear Instruments & Methods in Physics Research B, 2009, 267, 2601-2604.	0.6	10
74	Precise and fast secondary ion mass spectrometry depth profiling of polymer materials with large Ar cluster ion beams. Rapid Communications in Mass Spectrometry, 2009, 23, 1601-1606.	0.7	194
75	Molecular depth profiling of multilayer structures of organic semiconductor materials by secondary ion mass spectrometry with large argon cluster ion beams. Rapid Communications in Mass Spectrometry, 2009, 23, 3264-3268.	0.7	95
76	Study of crater formation and sputtering process with large gas cluster impact by molecular dynamics simulations. Nuclear Instruments & Methods in Physics Research B, 2009, 267, 1424-1427.	0.6	11
77	Stress measurement of carbon cluster implanted layers with in-plane diffraction technique. , 2009, , .		0
78	A Processing Technique for Cell Surfaces Using Gas Cluster Ions for Imaging Mass Spectrometry. Journal of the Mass Spectrometry Society of Japan, 2009, 57, 117-121.	0.0	1
79	A fragment-free ionization technique for organic mass spectrometry with large Ar cluster ions. Applied Surface Science, 2008, 255, 1588-1590.	3.1	58
80	MD simulation study of the sputtering process by high-energy gas cluster impact. Applied Surface Science, 2008, 255, 944-947.	3.1	11
81	Secondary ion emission from Si bombarded with large Ar cluster ions under UHV conditions. Applied Surface Science, 2008, 255, 880-882.	3.1	10
82	What size of cluster is most appropriate for SIMS?. Applied Surface Science, 2008, 255, 1235-1238.	3.1	44
83	Recent Progress in Cluster Ion Beam. Journal of Surface Analysis (Online), 2008, 14, 196-203.	0.1	6
84	Molecular dynamics study of monomer and dimer emission processes with high energy gas cluster ion impact. Surface and Coatings Technology, 2007, 201, 8427-8430.	2.2	5
85	Measurements of secondary ions emitted from organic compounds bombarded with large gas cluster ions. Nuclear Instruments & Methods in Physics Research B, 2007, 256, 493-496.	0.6	151
86	Secondary ion emission from bio-molecular thin films under ion bombardment. Nuclear Instruments & Methods in Physics Research B, 2007, 256, 489-492.	0.6	14
87	The effect of incident cluster ion energy and size on secondary ion yields emitted from Si. Nuclear Instruments & Methods in Physics Research B, 2007, 256, 528-531.	0.6	26
88	Size effect in cluster collision on solid surfaces. Nuclear Instruments & Methods in Physics Research B, 2007, 257, 627-631.	0.6	24
89	High-intensity Si cluster ion emission from a silicon target bombarded with large Ar cluster ions. Applied Surface Science, 2006, 252, 6550-6553.	3.1	7
90	Secondary ion measurements for oxygen cluster ion SIMS. Applied Surface Science, 2006, 252, 7290-7292.	3.1	6

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91	Total sputtering yields of solids under MeV-energy Si ion bombardment. Nuclear Instruments & Methods in Physics Research B, 2005, 230, 483-488.	0.6	2
92	Secondary neutral and ionized particle measurements under MeV-energy ion bombardment. Nuclear Instruments & Methods in Physics Research B, 2005, 230, 489-494.	0.6	2
93	Secondary-ion emission from III-V semiconductive materials under MeV-energy heavy-ion bombardment. Physical Review A, 2004, 70, .	1.0	2
94	Cluster-ion emission from semiconductive chemical compounds under MeV-energy heavy ion bombardment. Nuclear Instruments & Methods in Physics Research B, 2003, 209, 233-238.	0.6	4
95	Material-dependent emission mechanism of secondary atomic ions from solids under MeV-energy heavy ion bombardment. Nuclear Instruments & Methods in Physics Research B, 2002, 193, 745-750.	0.6	11
96	Emission energy distribution of secondary ions produced through the electronic sputtering process under heavy ion bombardment. Nuclear Instruments & Methods in Physics Research B, 2000, 164-165, 803-808.	0.6	8